

PCT

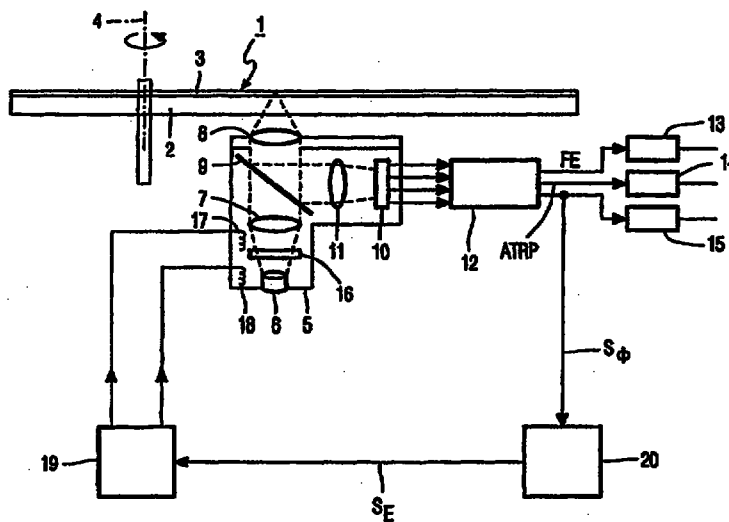
WORLD INTELLECTUAL PROPERTY ORGANIZATION
International Bureau



INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification ⁷ : G11B 7/095	A1	(11) International Publication Number: WO 00/10165 (43) International Publication Date: 24 February 2000 (24.02.00)
(21) International Application Number: PCT/EP99/05515 (22) International Filing Date: 29 July 1999 (29.07.99) (30) Priority Data: 1009829 10 August 1998 (10.08.98) NL (71) Applicant: KONINKLIJKE PHILIPS ELECTRONICS N.V. [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL). (72) Inventors: KAHLMAN, Josephus, A., H., M.; Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL). COENE, Willem, M., J.; Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL). (74) Agent: DE JONG, Durk, J.; Internationaal Octrooibureau B.V., Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).		(81) Designated States: CN, JP, KR, SG, European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE). Published <i>With international search report.</i>

(54) Title: APPARATUS FOR READING AN OPTICAL DATA CARRIER



(57) Abstract

An apparatus for reading an optical data carrier (1) in accordance with the invention, comprises a transducer (5) for optically reading an optically readable pattern recorded in substantially parallel data tracks of the data carrier (1). The transducer (5) generates a read signal ($S_0(t)$) which is an indication of the optically readable pattern. The apparatus further includes means for realizing a relative movement of the transducer (5) with respect to the data carrier (1). The apparatus also has correction means (16, 17, 18) for reducing tangential tilt (t_r) and error signal generating means (20) for generating an error signal ($S_E(t)$) for the correction means. The apparatus is characterized in that the error signal generating means (20) are adapted to derive the error signal ($S_E(t)$) from a temporal asymmetry of the response of the read signal ($S_0(t)$) to the optically readable pattern.